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Date Submitted: August 3, 2005

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Complete if Known			
Application Number	10/526,745		
Filing Date	03/07/2005		
First Named Inventor	Katsuya HASEGAWA		
Group Art Unit	Unassigned		
Examiner Name	Unassigned		
Attorney Docket Number	017700-0174		

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	Cite No. ¹	Number	Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear
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ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /K.M.V./

Examiner	/Kallambella Vijayakumar/	Date	00/05/0000
Signature	rranginoona vijayanaman	Considered	03/25/2008

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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